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Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

# 4V Drive Nch + Pch MOSFET

## QS8M13

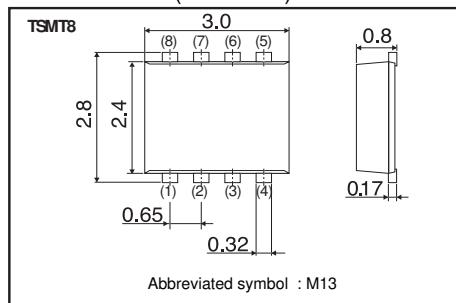
### ● Structure

Silicon N-channel MOSFET/  
Silicon P-channel MOSFET

### ● Features

- 1) Low on-resistance.
- 2) High power package(TSMT8).
- 3) Low voltage drive(4V drive).

### ● Dimensions (Unit : mm)



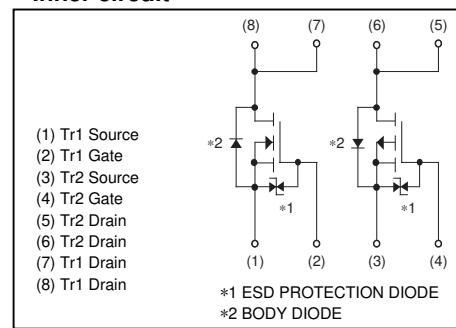
### ● Application

Switching

### ● Packaging specifications

Type	Package	Taping
	Code	TCR
QS8M13	Basic ordering unit (pieces)	3000

### ● Inner circuit



### ● Absolute maximum ratings (Ta = 25°C)

Parameter	Symbol	Limits		Unit
		Tr1 : N-ch	Tr2 : P-ch	
Drain-source voltage	V <sub>DSS</sub>	30	-30	V
Gate-source voltage	V <sub>GSS</sub>	±20	±20	V
Drain current	Continuous	I <sub>D</sub>	±6	A
	Pulsed	I <sub>DP</sub>	±18	A
Source current (Body Diode)	Continuous	I <sub>s</sub>	1.0	A
	Pulsed	I <sub>sp</sub>	18	A
Power dissipation	P <sub>D</sub>	1.5		W / TOTAL
		1.25		W / ELEMENT
Channel temperature	T <sub>ch</sub>	150		°C
Range of storage temperature	T <sub>stg</sub>	-55 to +150		°C

\*1 Pw≤10μs, Duty cycle≤1%

\*2 Mounted on a ceramic board.

## ● Electrical characteristics (Ta = 25°C)

&lt;Tr1(Nch)&gt;

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Gate-source leakage	I <sub>GSS</sub>	-	-	±10	µA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	30	-	-	V	I <sub>D</sub> =1mA, V <sub>GS</sub> =0V
Zero gate voltage drain current	I <sub>DSS</sub>	-	-	1	µA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V
Gate threshold voltage	V <sub>GS(th)</sub>	1.0	-	2.5	V	V <sub>DS</sub> =10V, I <sub>D</sub> =1mA
Static drain-source on-state resistance	R <sub>DS(on)</sub> *		-	20	28	I <sub>D</sub> =6A, V <sub>GS</sub> =10V
			-	25	35	I <sub>D</sub> =6A, V <sub>GS</sub> =4.5V
				28	39	I <sub>D</sub> =6A, V <sub>GS</sub> =4.0V
Forward transfer admittance	Y <sub>fs</sub>  *	3.0	-	-	S	V <sub>DS</sub> =10V, I <sub>D</sub> =6A
Input capacitance	C <sub>iss</sub>	-	390	-	pF	V <sub>DS</sub> =10V
Output capacitance	C <sub>oss</sub>	-	150	-	pF	V <sub>GS</sub> =0V
Reverse transfer capacitance	C <sub>rss</sub>	-	70	-	pF	f=1MHz
Turn-on delay time	t <sub>d(on)*</sub>	-	8	-	ns	I <sub>D</sub> =3A, V <sub>DD</sub> =15V
Rise time	t <sub>r</sub> *	-	40	-	ns	V <sub>GS</sub> =10V
Turn-off delay time	t <sub>d(off)*</sub>	-	35	-	ns	R <sub>L</sub> =5Ω
Fall time	t <sub>f</sub> *	-	7	-	ns	R <sub>G</sub> =10Ω
Total gate charge	Q <sub>g</sub> *	-	5.5	-	nC	I <sub>D</sub> =6A, V <sub>DD</sub> =15V
Gate-source charge	Q <sub>gs</sub> *	-	1.5	-	nC	V <sub>GS</sub> =5V
Gate-drain charge	Q <sub>gd</sub> *	-	2.1	-	nC	

\*Pulsed

## ● Body diode characteristics (Source-Drain) (Ta = 25°C)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Forward Voltage	V <sub>SD</sub> *	-	-	1.2	V	I <sub>s</sub> =6A, V <sub>GS</sub> =0V

\*Pulsed

## ● Electrical characteristics (Ta = 25°C)

&lt;Tr2(Pch)&gt;

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Gate-source leakage	I <sub>GSS</sub>	-	-	±10	µA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	-30	-	-	V	I <sub>D</sub> =-1mA, V <sub>GS</sub> =0V
Zero gate voltage drain current	I <sub>DSS</sub>		-	-1	µA	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V
Gate threshold voltage	V <sub>GS(th)</sub>	-1.0	-	-2.5	V	V <sub>DS</sub> =-10V, I <sub>D</sub> =-1mA
Static drain-source on-state resistance	R <sub>DS(on)</sub> *		-	28	39	I <sub>D</sub> =-5A, V <sub>GS</sub> =-10V
			-	40	56	I <sub>D</sub> =-2.5A, V <sub>GS</sub> =-4.5V
			-	45	63	I <sub>D</sub> =-2.5A, V <sub>GS</sub> =-4.0V
Forward transfer admittance	Y <sub>fs</sub>  *	3	-	-	S	V <sub>DS</sub> =-10V, I <sub>D</sub> =-5A
Input capacitance	C <sub>iss</sub>	-	1100	-	pF	V <sub>DS</sub> =-10V
Output capacitance	C <sub>oss</sub>	-	150	-	pF	V <sub>GS</sub> =0V
Reverse transfer capacitance	C <sub>rss</sub>	-	130	-	pF	f=1MHz
Turn-on delay time	t <sub>d(on)*</sub>	-	9	-	ns	I <sub>D</sub> =-2.5A, V <sub>DD</sub> =-15V
Rise time	t <sub>r</sub> *	-	40	-	ns	V <sub>GS</sub> =-10V
Turn-off delay time	t <sub>d(off)*</sub>	-	90	-	ns	R <sub>L</sub> =6Ω
Fall time	t <sub>f</sub> *	-	55	-	ns	R <sub>G</sub> =10Ω
Total gate charge	Q <sub>g</sub> *	-	10	-	nC	I <sub>D</sub> =-5A, V <sub>DD</sub> =-15V
Gate-source charge	Q <sub>gs</sub> *	-	3.6	-	nC	V <sub>GS</sub> =-5V
Gate-drain charge	Q <sub>gd</sub> *	-	3.0	-	nC	

\*Pulsed

## ● Body diode characteristics (Source-Drain) (Ta = 25°C)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Forward Voltage	V <sub>SD</sub> *	-	-	-1.2	V	I <sub>s</sub> =-5A, V <sub>GS</sub> =0V

\*Pulsed

●Electrical characteristic curves ( $T_a=25^\circ\text{C}$ )

⟨Tr.1(Nch)⟩

Fig.1 Typical Output Characteristics ( I )

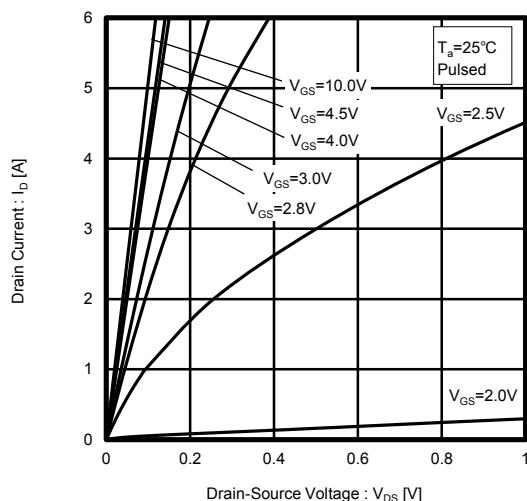


Fig.3 Static Drain-Source On-State Resistance vs. Drain Current

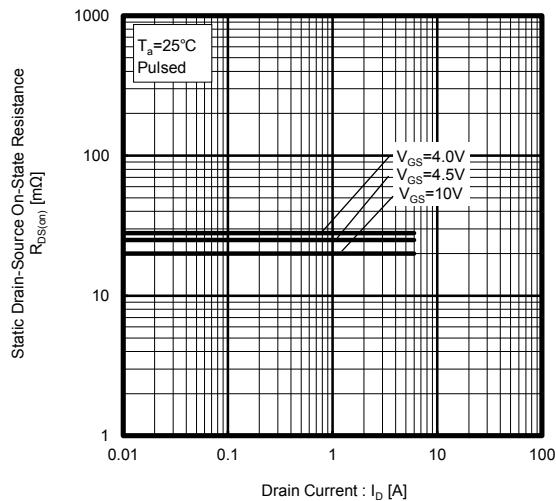


Fig.5 Static Drain-Source On-State Resistance vs. Drain Current

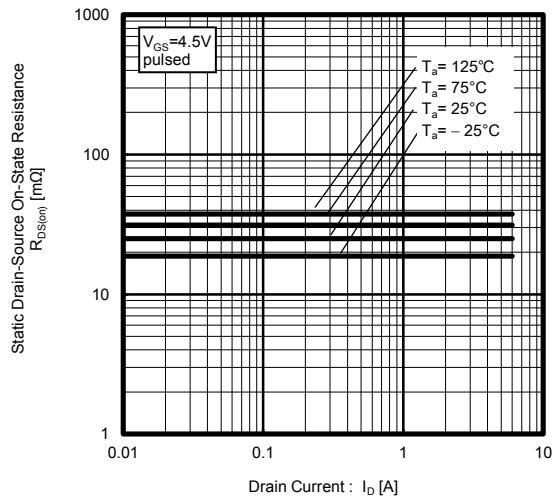


Fig.2 Typical Output Characteristics ( II )

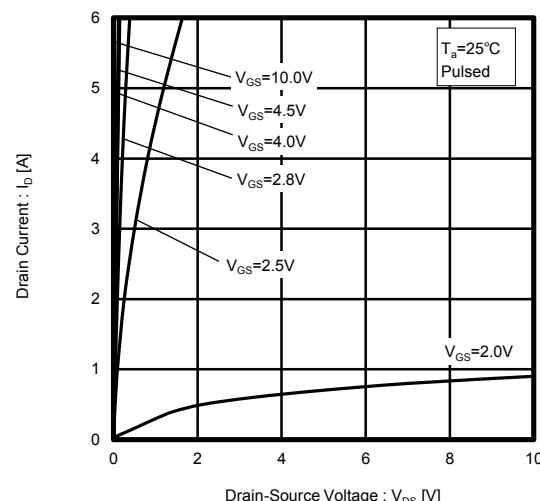


Fig.4 Static Drain-Source On-State Resistance vs. Drain Current

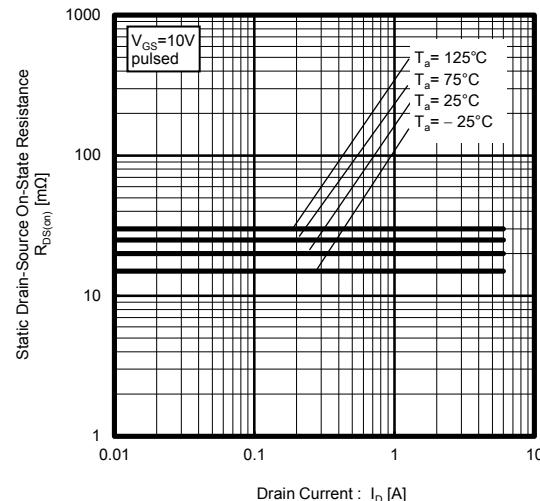


Fig.6 Static Drain-Source On-State Resistance vs. Drain Current

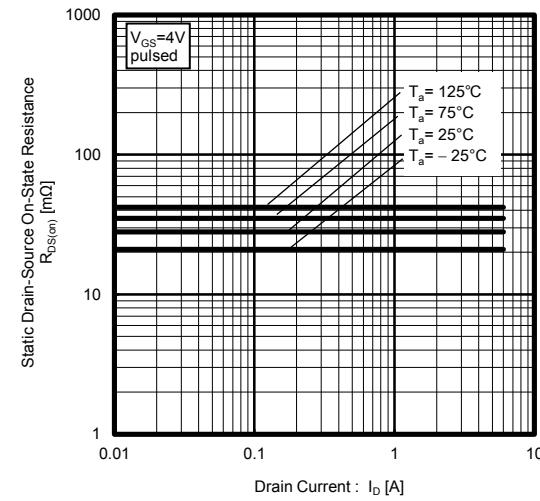


Fig.7 Forward Transfer Admittance vs. Drain Current

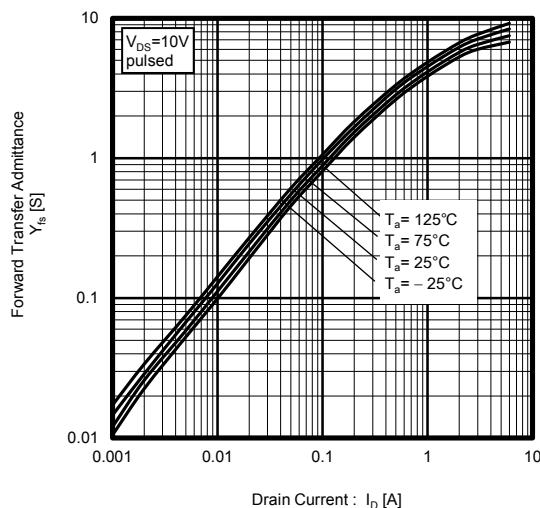


Fig.8 Typical Transfer Characteristics

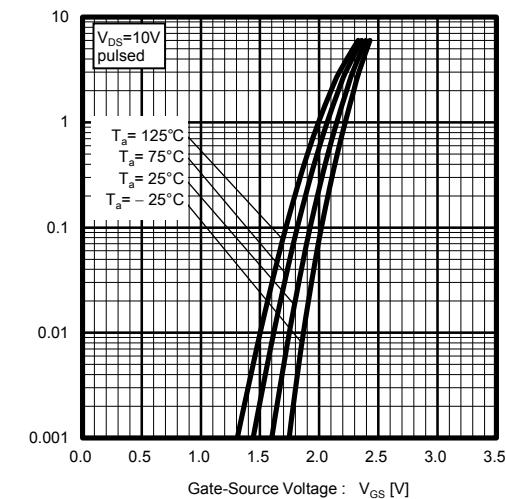


Fig.9 Source Current vs. Source-Drain Voltage

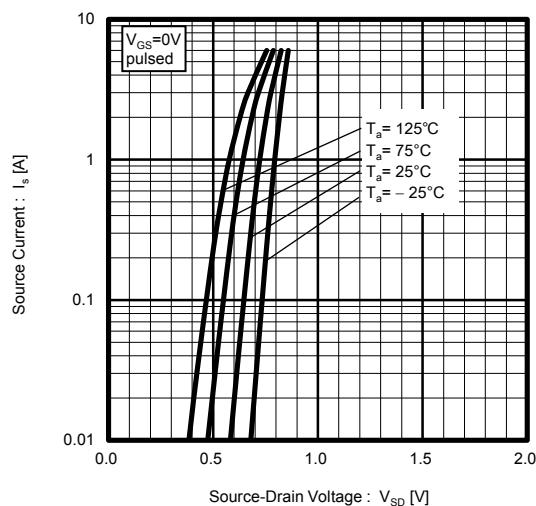


Fig.10 Static Drain-Source On-State Resistance vs. Gate-Source Voltage

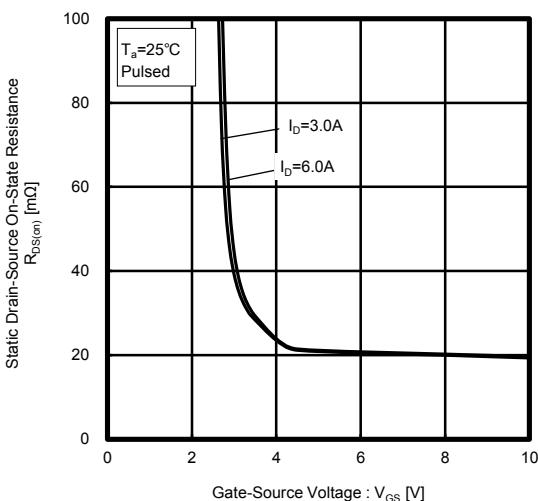


Fig.11 Switching Characteristics

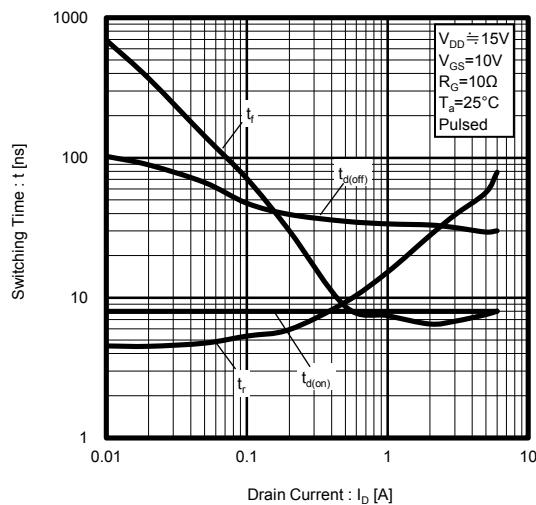


Fig.12 Dynamic Input Characteristics

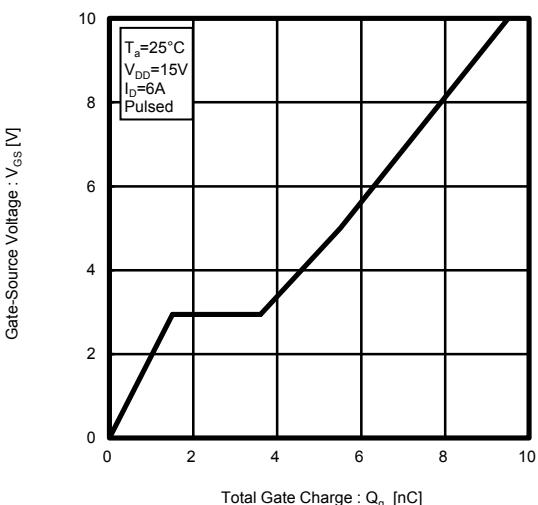


Fig.13 Typical Capacitance vs. Drain-Source Voltage

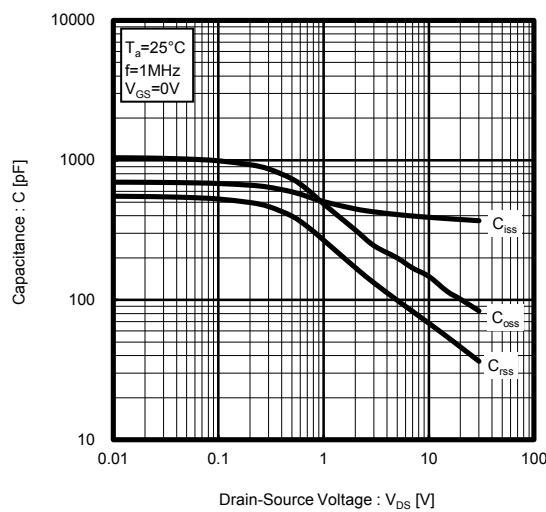


Fig.14 Maximum Safe Operating Area

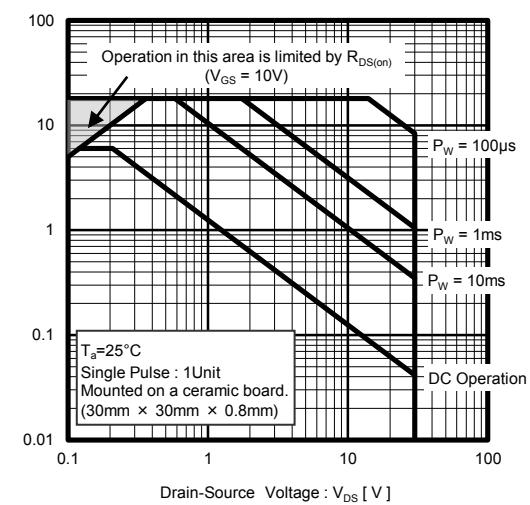
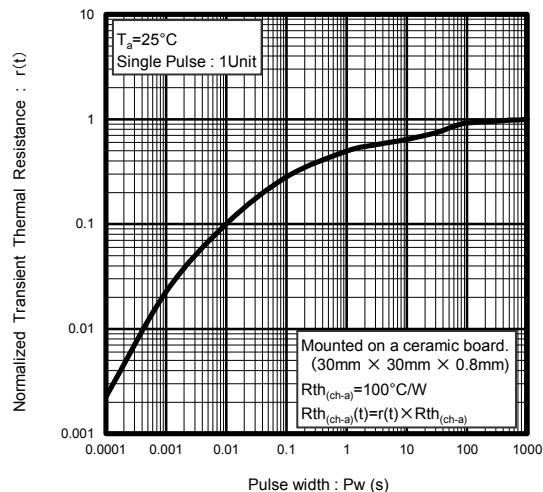


Fig.15 Normalized Transient Thermal Resistance v.s. Pulse Width



$\langle Tr.2(Pch) \rangle$ 

Fig.1 Typical Output Characteristics ( I )

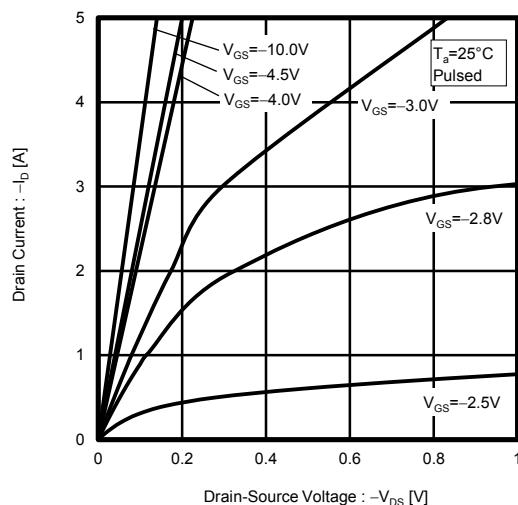


Fig.3 Static Drain-Source On-State Resistance vs. Drain Current

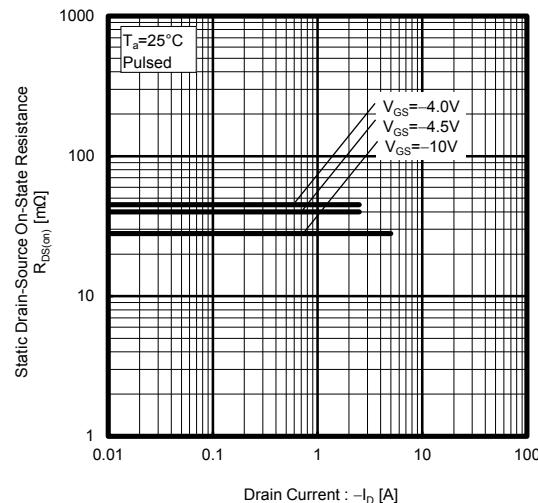


Fig.5 Static Drain-Source On-State Resistance vs. Drain Current

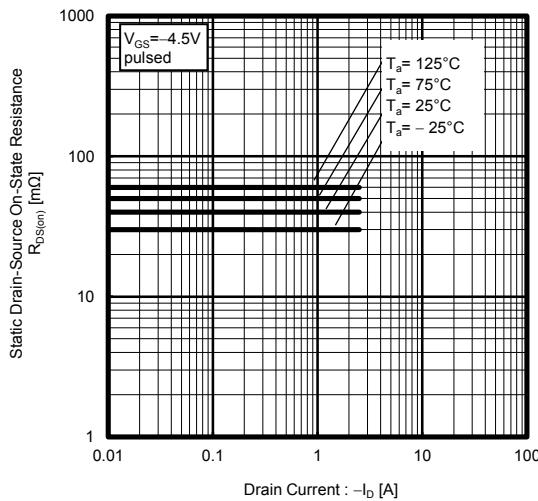


Fig.2 Typical Output Characteristics ( II )

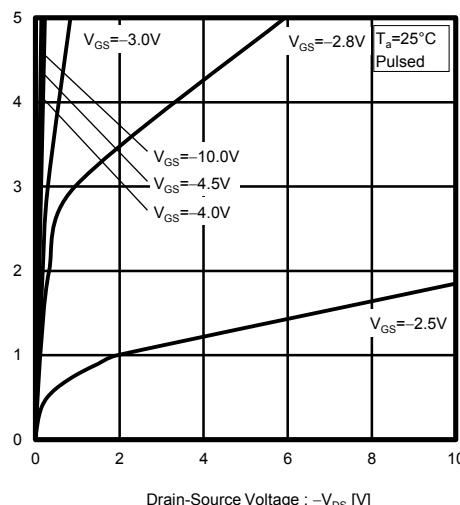


Fig.4 Static Drain-Source On-State Resistance vs. Drain Current

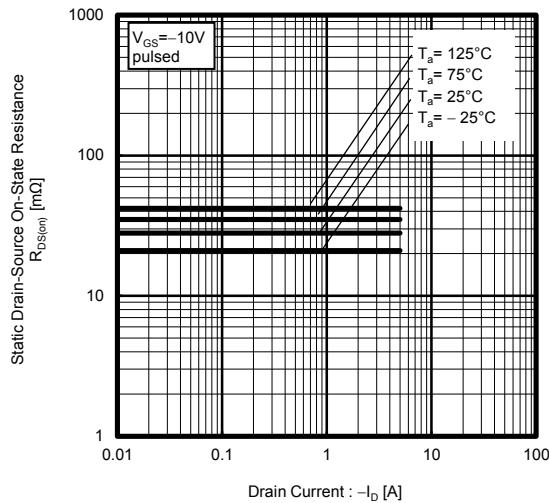


Fig.6 Static Drain-Source On-State Resistance vs. Drain Current

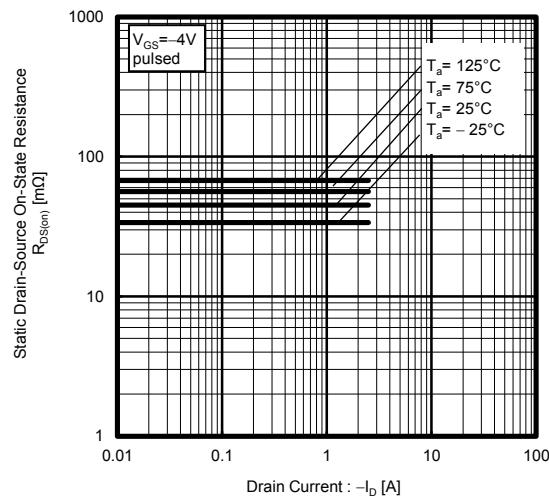


Fig.7 Forward Transfer Admittance vs. Drain Current

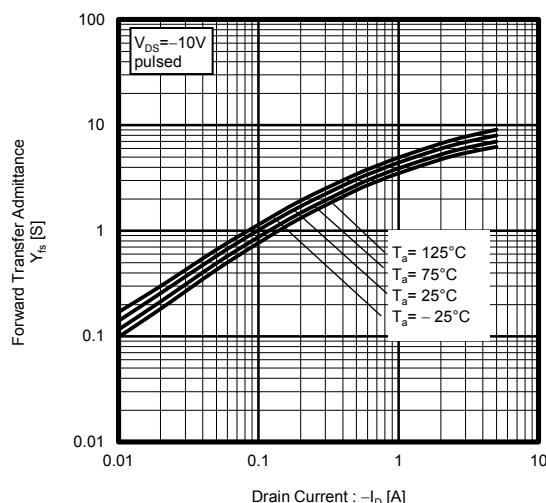


Fig.8 Typical Transfer Characteristics

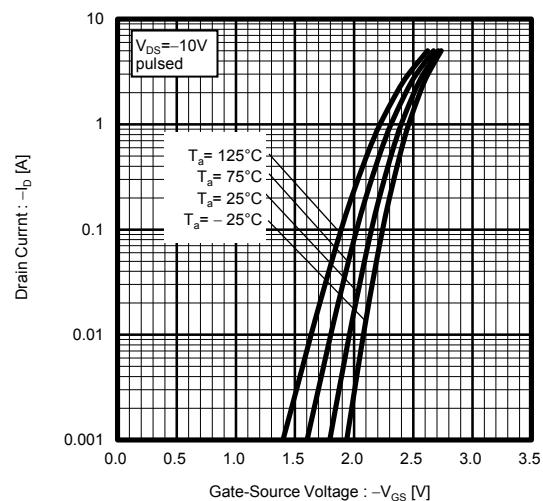


Fig.9 Source Current vs. Source-Drain Voltage

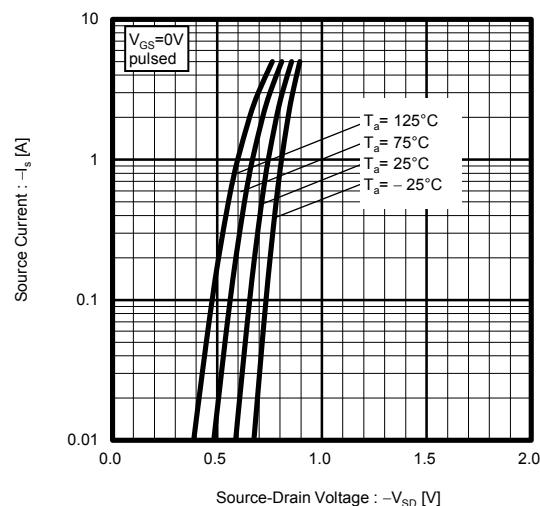


Fig.10 Static Drain-Source On-State Resistance vs. Gate-Source Voltage

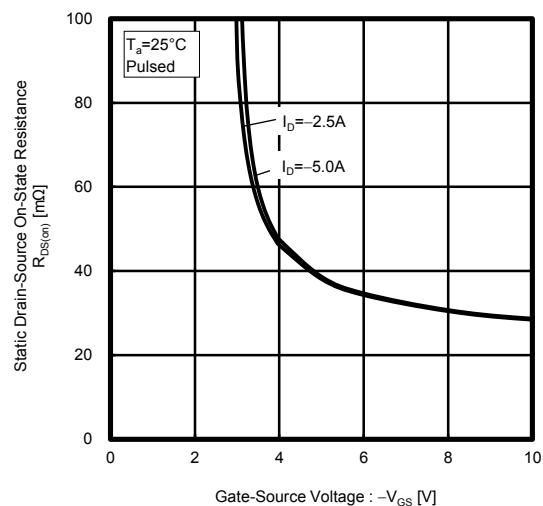


Fig.11 Switching Characteristics

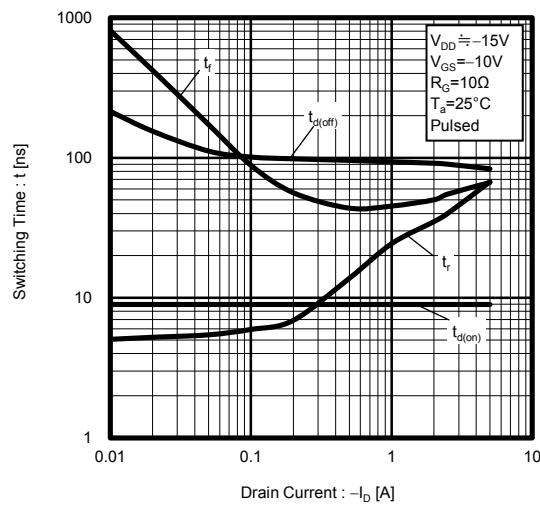


Fig.12 Dynamic Input Characteristics

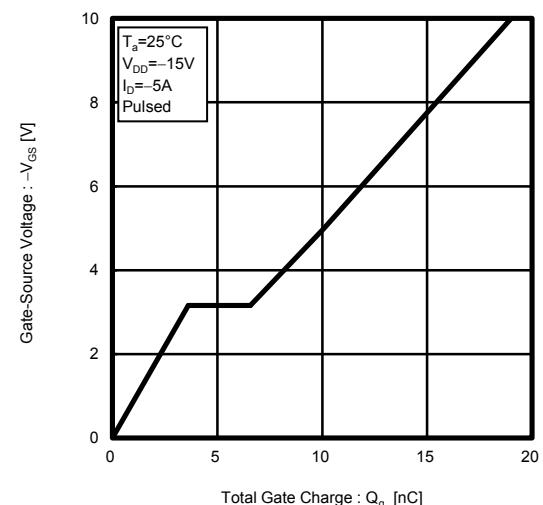


Fig.13 Typical Capacitance vs. Drain-Source Voltage

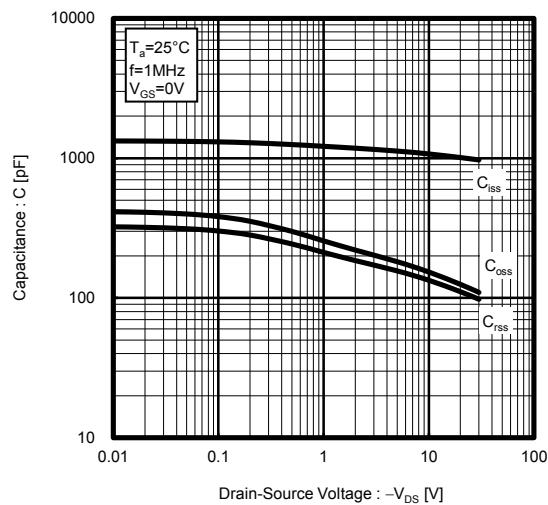


Fig.14 Maximum Safe Operating Area

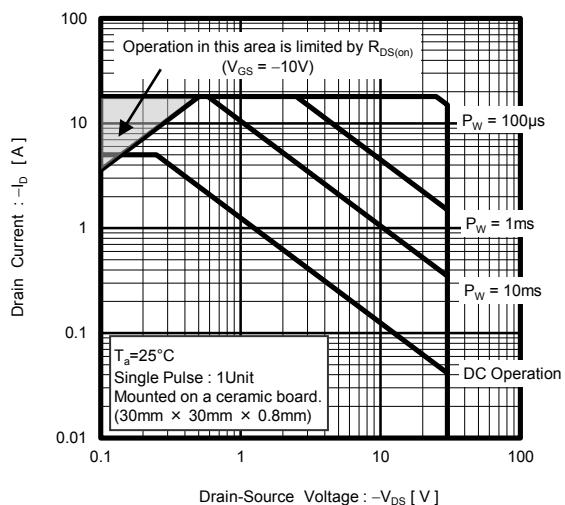
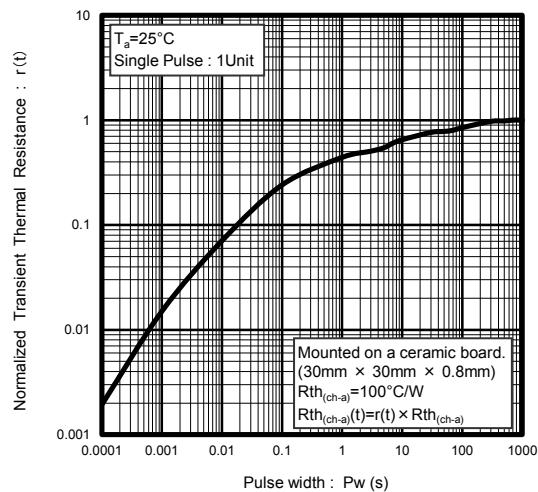


Fig.15 Normalized Transient Thermal Resistance v.s. Pulse Width



● Measurement circuits

<Tr1(Nch)>

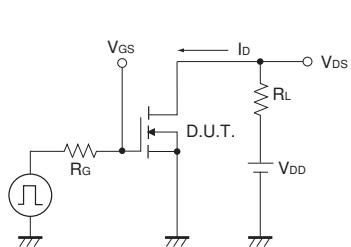


Fig.1-1 Switching Time Measurement Circuit

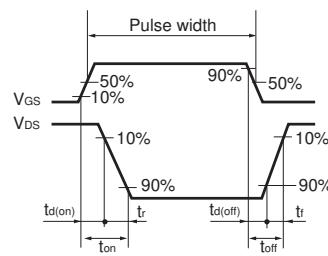


Fig.1-2 Switching Waveforms

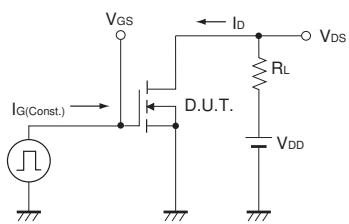


Fig.2-1 Gate Charge Measurement Circuit

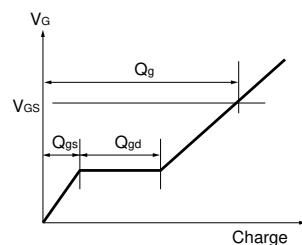


Fig.2-2 Gate Charge Waveform

<Tr2(Pch)>

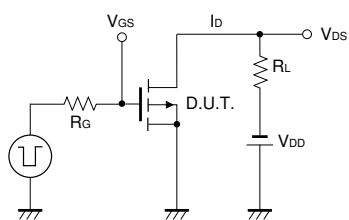


Fig.1-1 Switching Time Measurement Circuit

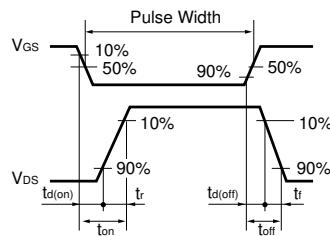


Fig.1-2 Switching Waveforms

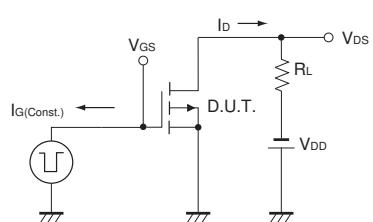


Fig.2-1 Gate Charge Measurement Circuit

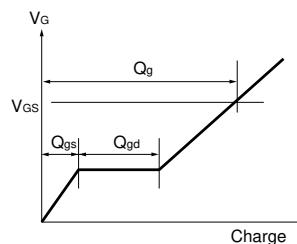


Fig.2-2 Gate Charge Waveform

● Notice

This product might cause chip aging and breakdown under the large electrified environment. Please consider to design ESD protection circuit.

## Notes

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